H53-869



Op-amps Comparators Voltage regulators Voltage references Analogue switches **Analogue multiplexers** Opto isolators Opto couplers DACS/ADCS Transistor arrays Special function Virtual grounds Audio

EXTENSIVE BUILT-IN TEST LIBRARY

Tests all common analogue ICs from Op-Amps to special function devices. New devices are added to the library continuously as they become available and released on EPROM every six months. Tests for customer's ICs not currently supported in the library can be added on request.

STATE OF THE ART **TECHNOLOGY**

Very large scale integration allows advanced functionality and ease of use to be combined in a hand-held, battery operated unit. The 2 line x 16 character dot matrix LCD shows the result of the test as a 'PASS' or 'FAIL' together with individual device pin diagnostics, test mode and possible equivalents.

Auto identification mode identifies unmarked/house-coded devices listing possible replacements

- Conditional/unconditional loop testing modes detect intermittent and temperature related faults
- Functional test-unit emulates passive circuitry to implement a comprehensive test in a variety of configurations and gain settings
- Displays diagnostic information down to individual component pins
- No programming or fixturing required
- Rugged, hand-held, ergonomically designed case incorporates built in membrane keypad, 2x16 dot matrix, alpha-numeric LCD and high quality 16 pin **ZIF** socket
- Battery operated (2xPP3) with low power design, auto power-down function and mains option
- Comprehensive manual included

AUTO **IDENTIFICATION**

The LinearMaster Compact automatically senses the functionality of the device to be tested and displays a list of possible equivalents for replacement. Unmarked and house-coded ICs are easily identified and tested.

COMPREHENSIVE TEST

The LinearMaster Compact emulates

passive circuitry around the device under test to ensure that a comprehensive test takes place. High integrity verification offers guaranteed levels of reliability in the results. Conditional and unconditional loop testing modes ensure that intermittent and/or temperature related faults are trapped.





PLATTS COMMON INDUSTRIAL PARK BARNSLEY, SOUTH YORKSHIRE S74 9TG TEL: (0226) 350145 FAX: (0226) 350 483